JUL 26 2007 BY

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re A	pplication of:	
	Tadashi MITSUI	Group Art Unit: 2609
Application No.: 10/807,187		Examiner: David RASHID
Filed:	March 24, 2004))
For:	PATTERN MEASURING APPARATUS, PATTERN MEASURING METHOD, AND MANUFACTURING METHOD OF	Confirmation No.: 3737

Mail Stop Amendment

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

AMENDMENT

In reply to the Office Action mailed March 26, 2007, the period for response having been extended to July 26, 2007, by a request for extension of one month and fee payment filed concurrently herewith, please amend the above-identified application as follows:

Amendments to the Specification are included in this paper.

Amendments to the Claims are reflected in the listing of claims in this paper.

Amendments to the Drawings are included in the attached replacement drawing sheets. The amendments are discussed in this paper and are also illustrated in the attached annotated drawing sheets.

Remarks/Arguments follow the amendment sections of this paper.

Attachments to this amendment include 3 replacement drawing sheets and 3 annotated drawing sheets.